

Search Notes**Application/Control No.**

10/699,613

Applicant(s)/Patent under Reexamination

DELEULE, ARNAUD

Examiner

Phallaka Kik

Art Unit

2825

SEARCHED

Class	Subclass	Date	Examiner
716	10,19	11/1/2005	PK
700	116,221	11/1/2005	PK
700	225	11/1/2005	PK
326	38,41,47	11/1/2005	PK
326	101	11/1/2005	PK
Above	updated	2/28/2006	PK
Above	new	2/28/2006	PK
700	115	2/28/2006	PK
257	758	2/28/2006	PK

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner
716	10,19	2/28/2006	PK
700	115	2/28/2006	PK
257	758	2/28/2006	PK
--USPGPUB (see attached)		2/28/2006	PK

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
BRS (EAST)--USPAT, USPGPUB Cls/Sub searched: 716/1-21; 700/115- 116,221-222,224-227; 326/38-50,101- 103; 438/6-10 (see attach)	11/1/2005	PK
Above updated and new search --additional cls/sub searched: 257/758,620,754.e23.179; 700/97,121 (see attached)	2/28/2006	PK
--EPO, JPO, IBM TDB, Derwent (see attached)	11/1/2005	PK
Consulted with Examiner Khoi Tran on similar case --no need to cross-reference to 700/213+	11/1/2005	PK
Consulted with Examiner Vibol Tan --no search or cross-referencing to class 326 is needed. Suggested search in class 257.	2/27/2006	PK
Consulted with Examiner Nathan W. Ha --suggested search and cross- referencing to 257/758	2/26/2006	PK
Consulted with Examiner Sean Shechtman on similar case --suggested search and cross- referencing to 700/115	2/23/2006	PK
IEE/IEEE Xplore (see attached)	11/1/2005	PK